

Notice of References Cited	Application/Control No. 09/878,519	Applicant(s)/Patent Under Reexamination BEAN ET AL.	
	Examiner Nhan T. Tran	Art Unit 2615	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,563,542	05-2003	Hatakenaka et al.	348/333.02
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP 2000-125165	04-2000	JAPAN	KAMIMURA TOKIO	H04N 5/225
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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